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List of Patents and Publications for Applicant's INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		Applicant Karin Scherer et al.	
		Filing Date: February 8, 2005	Group: 2874
U.S. Patent Documents <i>See Page 1</i>	Foreign Patent Documents <i>See Page 1</i>	Other Art <i>See Page 1</i>	

U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
/JL/	B1	EP 0 975 017	1/26/00	Europe			
/JL/	B2	EP 11264903	9/28/99	Japan			Abstract
/JL/	B3	JP 05215929	8/27/93	Japan			Abstract
/JL/	B4	WO 02/11195	2/7/02	WIPO			Abstract

Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
/JL/	C1	Lee and Hwangbo, "Inhomogeneous refractive index of SiOxy thin films prepared by ion beam assisted deposition," <i>Surface and Coatings Technology</i> , 128-129:280-285, 2000.

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EXAMINER: /Jonathan Langman/	DATE CONSIDERED: 06/22/2007
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